

12/28/06

Form PTO-1449

Sheet 1 of 2

Applicant: Naoki Fujiwara et al.
 Serial No.: 10/555,156
 Filing Date: November 2, 2005
 For: WAVELENGTH TUNABLE DISTRIBUTED BRAGG REFLECTOR (DBR) LASER
 (AMENDED)

Confirmation No.: 3941
 Att'y Docket No.: 14321.81
 Art Unit: 2828

INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANTU.S. Patent Documents

<u>Examiner Initial*</u>	<u>Document Number</u>	<u>Issue Date</u>	<u>Name</u>
/K.P./1	6,638,773 B1	10/28/2003	Hwang et al.

Foreign Patent Documents

<u>Examiner Initial*</u>	<u>Document Number</u>	<u>Publication Date</u>	<u>Country or Patent Office</u>	<u>Translation</u>
/K.P./2	03-044084	02/25/1991	Japan	No

Other Documents

(including author, title, pertinent pages, etc.)

Examiner Initial*

- /K.P./3 *Semiconductor Photonics Engineering, Section 7.6.4 – Distributed Bragg Reflector (DBR) Laser*, published under general editorship of Tatsuhiko Ikegami by Corona Corporation, January 10, 1995, pp. 306-311 (with partial English translation).
- /K.P./4 *Semiconductor Laser*, Chapter 13, [Compiled by Kenichi Iga (the Japan Society of Applied Physics)], published by Ohmsha, October 25, 1994, pp. 283-288 (with partial English translation).
- /K.P./5 Hiroyuki Ishii (reported by), *Research on High Performance Process of Wavelength Tuning Semiconductor Laser* (doctoral thesis), March 1999, pp. 39-43, 54-59, and 65-68 (with partial English translation).
- /K.P./6 Naoki Fujiwara et al., *Wavelength Selectable Mode-hop-free DBR Laser Array*, Technical Report of IEICE, OPE2003-33, 2003, pp. 47-50 (with partial English translation).

Examiner: /Kinam Park/ Date Considered: 08/15/2007

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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- /K.P./ 7 N. Fujiwara et al., *Mode-hop-free Wavelength-tunable Distributed Bragg Reflector Laser*, Electronics Letters, Vol. 39, No. 7, April 3, 2004, pp. 614-615.
- /K.P./ 8 Naoki Fujiwara et al., *Inherently Mode-Hop-Free Distributed Bragg Reflector (DBR) Laser Array*, IEEE Journal of Selected Topics in Quantum electronics, Vol. 9, No. 5, September/October 2003, pp. 1132-1137.

References Cited by Applicants

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The reference designations "A1," "A2," etc. (referring to Applicant's reference 1, Applicant's reference 2, etc.) will be used by the Examiner in the same manner as Examiner's reference designations "A," "B," "C," etc. on Office Action Form PTO-1142.

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Examiner:	/Kinam Park/	Date Considered:	08/15/2007
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SUPPLEMENTAL INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANTU.S. Patent Documents

Examiner <u>Initial*</u>	<u>Document Number</u>	<u>Issue Date</u>	<u>Name</u>
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Foreign Patent Documents

Examiner <u>Initial*</u>	<u>Document Number</u>	<u>Publication Date</u>	<u>Country or Patent Office</u>	<u>Translation</u>
/K.P./ 1	2003-110194	04/11/2003	Japan	No

Other Documents
(including author, title, pertinent pages, etc.)

Examiner
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References Cited by Applicants

While the filing of Information Disclosure Statements is voluntary, the procedure is governed by the guidelines of Section 609 of the Manual of Patent Examining Procedure and 37 C.F.R. §§ 1.97 and 1.98. To be considered a proper Information Disclosure Statement, Form PTO-1449 shall be accompanied by a copy of each listed patent or publication or other item of information and a translation of the pertinent portions of foreign documents (if an existing translation is readily available to the applicant), an explanation of relevance of each reference not in the English language, and should be submitted in a timely manner as set out in MPEP Sec. 609.

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